

**Search Notes**

Application/Control No.

10/073,850

Examiner

J. Derek Rутten

Applicant(s)/Patent under  
Reexamination

LI ET AL.

Art Unit

2192

**SEARCHED**

Class	Subclass	Date	Examiner
717	105,125, 127	5/19/2006	JDR
715	767 771	5/19/2006	JDR
715	854	5/19/2006	JDR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
717	105, 125	5/19/2006	JDR
717	127	5/19/2006	JDR
715	767, 771	5/19/2006	JDR
715/854		5/19/2006	JDR

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	5/11/2006	JDR
Antony Nguyen-Ba (re. allowable subject matter)	5/11/2006	JDR
717/105,125; 715/764,771,853,854 - Text search only - see search notes printout	5/11/2006	JDR
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	5/12/2006	JDR
ACM - portal.acm.org IEEE - ieeexplore.ieee.org See search history printout	5/12/2006	JDR